

1. Scope

This specification is applies to Multilayer Ceramic Chip Capacitor (MLCC) for use in electric equipment for the voltage is ranging from 100V to 5KV.

The MLCC support for Lead-Free wave and reflow soldering, and electrical characteristic and reliability are same as before. (This product compliant with the RoHS.)

2. Parts Number Code

С	1812	Х	474	K	101	Т
(1)	(2)	(3)	(4)	(5)	(6)	(7)

(1)Product

Product Code	
С	Multilayer Ceramic Chip Capacitor

(2)Chip Size

(_) F		
Code	Length×Width	unit : mm(inch)
0201	0.60× 0.30	(.024× .011)
0402	1.00× 0.50	(.039× .020)
0603	1.60× 0.80	(.063× .031)
0805	2.00× 1.25	(.079× .049)
1206	3.20× 1.60	(.126× .063)
1210	3.20× 2.50	(.126× .098)
1808	4.60× 2.00	(.181× .079)
1812	4.60× 3.20	(.181× .125)
1825	4.60× 6.35	(.181× .250)
2208	5.70× 2.00	(.220× .197)
2211	5.70× 2.80	(.220× .110)
2220	5.70× 5.00	(.220× .197)
2225	5.70× 6.35	(.220× .250)

(3)Temperature Characteristics

	_		
Code	Temperature	Temperature	Temperature
	Characteristic	Range	Coefficient
Ν	NPO	-55°℃~+125°℃	30 ppm/°C
L	SL	-30°C ~+85°C	+350~-1000ppm
X	X7R	-55℃~+125℃	± 15%
В	X5R	-55°C ~+85°C	± 15%
S	X6S	-55°℃~+105°℃	± 22%
Υ	Y5V	-30°C ~+85°C	+22/-82%
Z	Z5U	+10°℃~+85°℃	+22/-56%
Е	Y5U	-30°C ~+85°C	+22/-56%

(4)Capacitance unit :pico farads(pF)

· / I	1 4 /
Code	Nominal Capacitance (pF)
5R0	5.0
120	12.0
151	150.0
222	2,200.0
103	10,000.0
474	470,000.0
105	1,000,000.0
106	10,000,000.0

^{**.} If there is a decimal point, it shall be expressed by an

(5) Capacitance Tolerance

Tolerance	Nominal Capacitance
± 0.10 pF	Less Than 10 pF
± 0.25 pF	(Include 10 pF)
± 0.50 pF	
± 1.00 pF	_
± 1.00 %	More Than 10 pF
± 2.00 %	
± 5.00 %	
± 10.0 %	_
± 20.0 %	
+80/-20 %	
	± 0.10 pF ± 0.25 pF ± 0.50 pF ± 1.00 pF ± 1.00 % ± 2.00 % ± 5.00 % ± 10.0 %

(6)Rated Voltage

Code	Rated Voltage (Vdc)
101	100
201	200
251	250
501	500
631	630
102	1,000
202	2,000
252	2,500
302	3,000
502	5,000

(7)Tapping

Code	Type	
Т	Tape & Reel	
В	Bulk	

English capital letter R

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3. Nominal Capacitance and Tolerance

3.1 Standard Combination of Nominal Capacitance and Tolerance

Class	Characteristic	Tolera	ance	Nominal Capacitance
I	NPO / SL	Less Then 10 pF	B (± 0.10 pF)	0.5,1,1.5,2,2.5,3
			C (± 0.25 pF)	0.5,1,1.5,2,2.5,3,3.5,4,4.5,5
			D (± 0.50 pF)	5,6,7,8,9,10
			E (± 1.00 pF)	6,7,8,9,10
		More Than 10 pF	F (±1.00 %)	E-12, E-24 series
			G (±2.00 %)	
			J (± 5.00 %)	
			K (± 10.0 %)	
П	X7R/X5R/X7E	K (± 10.0 %),	M (± 20.0 %)	E-3, E-6 series
	Y5V	M (± 20.0 %), Z	Z(+80/-20 %)	E- 3 series
	Z5U			
	Y5U			

3.2 E series(standard Number)

Standard No.	Application Capacitance											
E- 3		1.0 2.2						4	.7			
E- 6	1.	.0	1	.5	2	.2	3	.3	4	.7	6	.8
E-12	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
E-24	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
	1.1	1.3	1.6	2.0	2.4	3.0	3.6	4.3	5.1	6.2	7.5	9.1

4. Operation Temperature Range

Class	Characteristic	Temperature Range	Reference Temp.
I	NPO	-55℃ ~ +125℃	25 ℃
	SL	-25℃ ~ +125℃	25 ℃
П	X7R	-55℃ ~ +125℃	25℃
	X5R	-55℃ ~ +85℃	25 ℃
	X6S	-55°C ~ +105°C	25 ℃
	Y5V	-30℃ ~ +85℃	25 ℃
	Z5U	+10℃ ~ +85℃	25 ℃
	Y5U	-30°C ~ +85°C	25 ℃
	Other	-25℃ ~ +85℃	25 ℃

5. Storage Condition

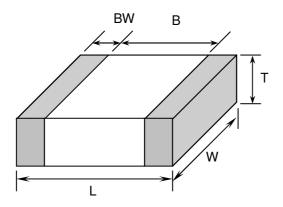
Storage Temperature : 5 to 40° C Relative Humidity : 20 to 70 % Storage Time : 6 months max.

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6. Dimensions

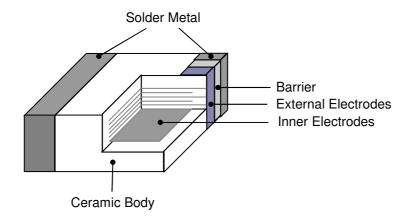
6.1 Configuration and Dimension:



Unit:mm

TYPE	L	W	Т	B (min)	BW (min)
1812	4.60± 0.30	3.20± 0.30	1.60± 0.20	2.50	0.30

6.2 Termination Type :





7. Performance

No.	Item		9	Specification	Test Condition		
1	Visua	ıl	No abnormal	exterior appearance	Visual inspection		
2	Dimens	ion	See Page 3		Visual inspection		
3	Insulati Resista		10,000MΩ or Product Whice	r 500/C Ω chever Is Smaller	V≦500V, Rated Voltage V>500V, Applied 500Vdc Charge Time: 60sec. Is applied less than 50mA current.		
4	Capacitance	I	Within The Sp	ecified Tolerance	Class I:		
		NPO/SL			NPO/SL		
		Class II	Within The Sp	ecified Tolerance	CapacitanceFrequencyVoltageC≤100pF1MHz±10%1.0±0.2VrmsC>100pF1KHz±10%		
5	Q	Class		pF : Q ≧ 1000	Class II :		
		I NPO/SL		r: Q≥400+20C	Frequency Voltage X7R 1KHz±10% 1.0±0.2Vrms		
	Tan δ	Class	Char.	Maximum	Z5U/Y5U 1KHz±10% 1.0±0.2Vrms		
	ian o	Ulass	X7R	2.5%	Perform a heat temperature at 150±5°C for		
			Z5U/Y5U	4.0%	30min. then place room temp. for 24±2hr.		
6	Withstan Voltag	-	mechanical b	breakdown or oreakdown	V < 500V : 200% Rated Voltage 500V ≤ V < 1000V: 150% Rated Voltage 1000 ≦ V : 120% Rated Voltage for 1~5 sec. Current is limited to less than 50mA. ※ Withstanding voltage testing requires immersion of the element in a isolation fluid prevent arcing on the chip surface, at voltage over 1000Vdc.		
7	Temperature Capacitance Coefficient	Class I Class	Char. Temp. F NPO -55°C ~- SL -30°C ~- Char. Temp. F X7R -55°C ~- Y5U -30°C ~- Z5U +10°C ~-	+125°C ± 30 ppm/°C +85°C +350~-1000ppm Range Cap. Change(%) +125°C ± 15% +485°C +22% ~-56%	Class I: [C2-C1/C1(T2-T1)] × 100% Class II: (C2-C1)/C1 × 100% T1: Standard temperature (25°C) T2: Test temperature C1:Capacitance at standard temperature(25°C) C2: Capacitance at test temperature (T2)		
8	Adhesive S of Termin	ation	No indication of peeling shall occur on the terminal electrode.		A 5N·f (≒0.5Kg·f) pull force shall be applied for 10± 1 second. 5N·f		
9	to	Appear- ance			Bending shall be applied to the 1.0 mm with 1.0 mm/sec.		
	Flexure of Substrate	C-Meter	Capacitance C Char. NPO SL X7R Y5U/Z5U	Change Cap. Change ≤ ± 5.0% ≤ ± 5.0% ≤ ± 12.5% ≤ ± 30.0%	Bending Limit C Meter 45±1mm 45±1mm		



No.	Ite	m	•	cification	Test Condition	
10	Solder	ability		f the terminal surface newly, so metal part ut or dissolve .	Solder Temperature: 245±5°C Dip Time: 5 ± 0.5 sec. Immersing Speed: 25±10% mm/s Solder: H63A Flux:Rosin Preheat: At 80~120°C for 10~30sec.	
11	Resistance To	Appear- ance	S S		Class II capacitor shall be set for 48±4 hours at room temperature after one hour heat	
	Soldering Heat	Capacit- ance	Characteristic	Cap. Change Within ± 2.5% or	treatment at 150 +0/-10°C before initial measure.	
			(NPO/SL)	±0.25pFwhichever is larger of initial value	Dip : Solder Temperature of 260± 5°C Dip Time : 10 ± 1sec.	
			Class X7R II Z5U/Y5U	Within ± 10% Within ± 20%	Immersing Speed : 25±10% mm/s Solder : H63A	
		Q Class I		cified initial value	Flux :Rosin	
		Tan δ Class ${\rm II}$	To satisfy the spe		Measure at room temperature after cooling for Class I: 24 ± 2 Hours Class I: 48 ± 4 Hours	
		Insulation Resistance Withstand			- Class H : 10 2 T Floure	
		Voltage	, '			
12	Tempera	Appear- ance		amage shall occur	Class ☐ capacitor shall be set for 48± 4 hours at room temperature after one hour heat treatment	
	Cycle	Capacit- ance	Characteristic Class I (NPO/SL)	Cap. Change Within ± 2.5% or ±0.25pFwhichever is larger of initial value	the temperature cycle as following:	
			Class X7R II Z5U/Y5U	Within ± 7.5%	Step Temp.(°C) Time(min) 1 Min Rated Temp. +0/-3 30	
		Q Class I	ļ — I	cified initial value	2 25 3 3 Max Rated Temp. +3/-0 30 4 25 3	
			To satisfy the spe	cified initial value	Measure at room temperature after cooling for	
			To satisfy the spe	cified initial value	Class I:24 ± 2 Hrs Class II:48 ± 4 Hrs Solder the capacitor on P.C. board shown in Fig 2. before testing.	
13	Humidity	Appear- ance	No mechanical da	amage shall occur	Class ☐ capacitor shall be set for 48± 4 hours at room temperature after one hour heat	
		Capacit- ance	Characteristic Class I (NPO/SL)	Cap. Change Within ± 5.0% or ±0.5pF whichever is larger of initial value	treatment at $150+0/-10~\%$ before initial measure. Temperature : $40\pm2\%$ Relative Humidity : $90\sim95\%$ RH	
			Class X7R II Z5U/Y5U		Test Time: 500 + 12/-0Hr	
		Q Class I	More Than 30pF 30pF & Below: Q		Measure at room temperature after cooling for Class I: 24 ± 2Hrs Class II: 48 ± 4Hrs	
		Tan δ Class II	Char. X7R	Maximum 5.0%	-	
			Z5U/Y5U	5.0%	 Solder the capacitor on P.C. board shown in Fig 2. before testing. 	
		Resistance		C Ω whichever is		
1	1	1	1			

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No.	Item			9	Specific	cation		Test Condition		
14	High Temperature	Appear- ance	No me	echanica	ıl damı	age shall occur		ass II capacitors appollowing table) is app	_	
	Load	Capacit-	Ch	aracteris	stic	Cap. Change	maximum operation temperature ±3°C then			
	(Life Test)	ance	Class			Within ±3.0% or	-	•	urs at room temperature	
			(NPO	SL)		± 0.3pFwhichever		nd the initial measurer	•	
						is larger	CC	onducted.		
			Class			Within ± 15%	Αŗ	oplied Voltage :		
			П	Z5U/`		Within ± 30%		-		
		Q		Than 30				Rated Voltage	Applied Voltage	
		Class I			:Q ≧ 2	275 + 2.5× C		V≤250Vdc	150%Rated Voltage	
		Tan δ		har.		maximum		Less Than 1KVdc	120%Rated Voltage	
		Class II		7R J/Y5U		5.0% 5.0%		More Than	100%Rated Voltage	
		Inculatio				whichever is		1KVdc(include 1KV)	100 /61 lated voltage	
		n	smalle			(C in Farad)				
		Resistan	1	,,,		(O III i didd)		210/100V capacitance		
		се						plied voltage of 120%		
								emperature : max. ope est Time : 1000 +12/-0		
								urrent Applied: 50 m/		
									erature after cooling for	
								ass I : 24 \pm 2 Hours	orator o artor ocoming roll	
							CI	ass		
15	Vibration	Appear-	No me	echanica	ıl dama	age shall occur	S	Solder the capacitor o	n P.C. Board shown in	
		ance					F	ig 2. before testing.		
		Capacit-		aracteris	stic	Cap. Change	١.	,		
		ance	Class			Within ± 2.5% or			vith amplitude of 1.5mm	
			(NPO	(SL)		± 0.25pFwhichever		5-P changing the freq 55Hz and back to 10F	uencies from 10Hz to	
			Class	X7	D	is larger Within ± 7.5%		SHZ and back to fur	12 III about 1 IIIIII.	
			Class	Z5U/`		Within ± 7.5%	R	eneat this for 2 hours	each in 3perpendicular	
		Q				ed initial value		rections.	odon m oporpondiodidi	
		Class I	10 341	isiy tilo .	эрссііі	ca miliai value	3.00.000			
		Tan δ	To sat	isfy the	specifi	ed initial value	1			
		Class ∏		,	•					
		Insulatio	To sat	isfy the	specifi	ed initial value				
		n								
		Resistan								
		ce								



Fig.1
P.C. Board for Bending Strength Test

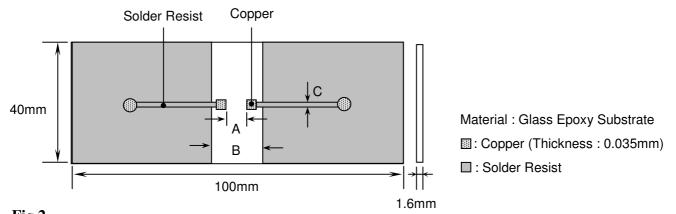
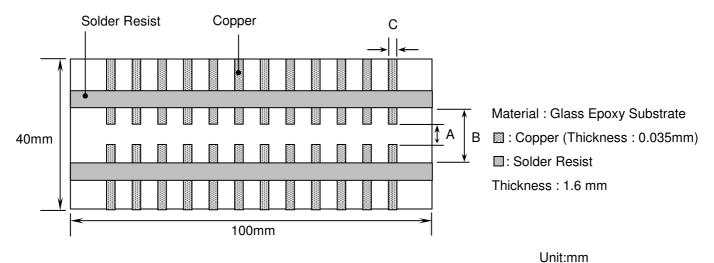


Fig.2 Test Substrate



Type	Α	В	С
0201	0.2	0.9	0.4
0402	0.5	1.5	0.6
0603	1.0	3.0	1.0
0805	1.2	4.0	1.6
1206	2.2	5.0	2.0
1210	2.2	5.0	2.9
1808	3.5	7.0	2.5
1812	3.5	7.0	3.7
2208	4.5	8.0	2.5
2211	4.5	8.0	3.0
2220	4.5	8.0	5.6

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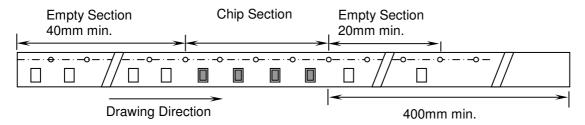


8. Packing

8.1 Bulk Packing

According to customer request.

8.2 Chip Capacitors Tape Packing



8.3 Material And Quantity

Tape	0201	0402	0603/0805	
Material	T≦0.33mm	T≦0.55mm	T≦0.90mm	T>0.90mm
Paper	15,000 pcs/Reel	10,000 pcs/Reel	4,000 pcs/Reel	NA
Plastic	NA	NA	NA	3,000 pcs/Reel

Tape		1206	1210/	1808	
Material	T≦0.90mm	0.90mm < T ≤ 1.25mm	T>1.25mm	T≦1.25mm	T>1.25mm
Paper	4,000 pcs/Reel	NA	NA	NA	NA
Plastic	NA	3,000 pcs/Reel	2,000 pcs/Reel	3000 pcs/Reel	2000 pcs/Reel

Tape	1812/1825	/2211/2220	22	25	2208
Material	T≦2.20mm	T>2.20mm	T≦2.20mm	T>2.20mm	T≦2.20mm
Paper	NA	NA	NA	NA	NA
Plastic	1000 pcs/Reel	700 pcs/Reel	1000 pcs/Reel	400 pcs/Reel	1000 pcs/Reel

NA: Not Available

8.4 Cover Tape Reel Off Force

8.4.1 Peel-Off Force

 $5 g \cdot f \leq Peel-Off Force \leq 70 g \cdot f$

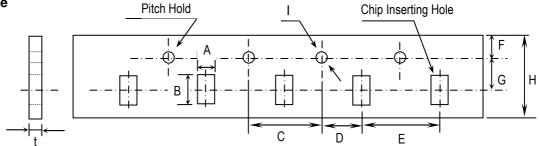
8.4.2 Measure Method



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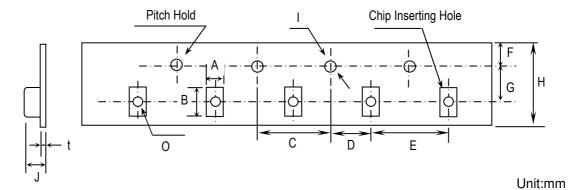


Unit:mm

TYPE	Α	В	С	D	E
0201	0.37± 0.1	0.67± 0.1	4.00± 0.1	2.00± 0.05	2.00± 0.1
0402	0.61± 0.1	1.20± 0.1			
0603	1.10± 0.2	1.90± 0.2			4.00± 0.1
0805	1.50± 0.2	2.30± 0.2			
1206	1.90± 0.2	3.50± 0.2			
1210	2.90± 0.2	3.60± 0.2			

TYPE	F	G	Н		t
0201	1.75± 0.10	3.50± 0.05	8.0± 0.30	φ 1.50 +0.10/-0	1.10 max.
0402					
0603					
0805					
1206					
1210					

8.6 Plastic Tape



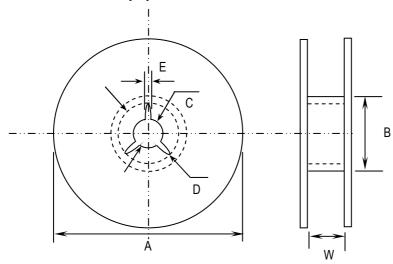
Type	Α	В	С	D	E	F
0805	1.5±0.2	2.3±0.2	4.0± 0.1	2.0± 0.05	4.0± 0.1	1.75± 0.1
1206	1.9±0.2	3.5±0.2				
1210	2.9±0.2	3.6±0.2				
1808	2.5±0.2	4.9±0.2				
1812	3.6±0.2	4.9±0.2			8.0± 0.1	
1825	6.9±0.2	4.9±0.2				
2208	2.5±0.2	6.1±0.2				
2211	3.2±0.2	6.1±0.2				
2220	5.4±0.2	6.1±0.2				
2225	6.9±0.2	6.1±0.2				



Туре	G	Н	I	J	t	0
0805	3.5± 0.05	8.0± 0.3	φ 1.5+0.1/-0	3.0 max.	0.3 max.	0.15 min.
1206						
1210						
1808	5.5± 0.05	12.0 ± 0.3		4.0 max.		
1812						
1825						
2208						
2211						
2220						
2225						

8.7 Reel Dimensions

Reel Material : Polystyrene



Unit:mm

Туре	Α	В	С	D	E	W
0201	φ 382 max	arphi 50 min	φ 13± 0.5	φ 21± 0.8	2.0±0.5	10± 0.15
0402						
0603						
0805						
1206						
1210						
1808	φ 178±0.2	φ 60±0.2				13±0.3
1812						
1825						
2208						
2211						
2220						
2225						

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Precautionary Notes:

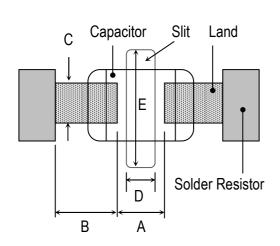
1. Storage

Store the capacitors where the temperature and relative humidity don't exceed 40 °C and 70%RH. We recommend that the capacitors be used within 6 months from the date of manufacturing. Store the products in the original package and do not open the outer wrapped, polyethylene bag, till just before usage. If it is open, seal it as soon as possible or keep it in a desiccant with a desiccation agent.

2. Construction of Board Pattern

Improper circuit layout and pad/land size may cause excessive or not enough solder amount on the PC board. Not enough solder may create weak joint, and excessive solder may increase the potential of mechanical or thermal cracks on the ceramic capacitor. Therefore we recommend the land size to be as shown in the following table:

2.1 Size and recommend land dimensions for reflow soldering .

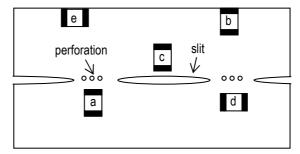


EIA Codo	Chip (mm)		Land (mm)				
EIA Code	L	W	Α	В	С	D	Е
0201	0.60	0.30	0.2~0.3	0.2~0.4	0.2~0.4		
0402	1.00	0.50	0.3~0.5	0.3~0.5	0.4~0.6		
0603	1.60	0.80	0.4~0.6	0.6~0.7	0.6~0.8		1
0805	2.00	1.25	0.7~0.9	0.6~0.8	0.8~1.1		1
1206	3.20	1.60	2.2~2.4	0.8~0.9	1.0~1.4	1.0~2.0	3.2~3.7
1210	3.20	2.50	2.2~2.4	1.0~1.2	1.8~2.3	1.0~2.0	4.1~4.6
1808	4.60	2.00	2.8~3.4	1.8~2.0	1.5~1.8	1.0~2.8	3.6~4.1
1812	4.60	3.20	2.8~3.4	1.8~2.0	2.3~3.0	1.0~2.8	4.8~5.3
1825	4.60	6.35	2.8~3.4	1.8~2.0	5.1~5.8	1.0~4.0	7.1~8.3
2208	5.70	2.00	4.0~4.6	2.0~2.2	1.5~1.8	1.0~4.0	3.6~4.1
2211	5.70	2.80	4.0~4.6	2.0~2.2	2.0~2.6	1.0~4.0	4.4~4.9
2220	5.70	5.00	4.0~4.6	2.0~2.2	3.5~4.8	1.0~4.0	6.6~7.1
2225	5.70	6.35	4.0~4.6	2.0~2.2	5.1~5.8	1.0~4.0	7.1~8.3

2.2 Mechanical strength varies according to location of chip capacitors on the P.C. board.

Design layout of components on the PC board such a way to minimize the stress imposed on the components, upon flexure of the boards in depanelization or other processes.

Component layout close to the edge of the board or the "depanelization line" is not recommended. Susceptibility to stress is in the order of: a>b>c and d>e



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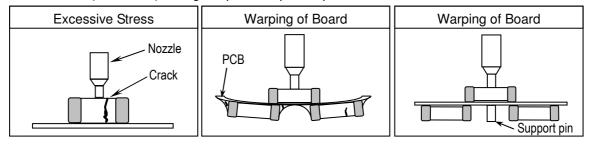


2.3 Layout Recommendation

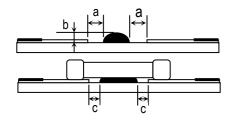
Example	Use of Common Solder Land	Solder With Chassis	Use of Common Solder Land With Other SMD
Need to Avoid	Chip Solder Adhesive PCB Solder Land	Chassis Excessive Solder a	Solder Land
Recommendation	Chip Solder Resist Adhesive PCB Solder Land	Solder Resist $\alpha > \beta$	

3. Mounting

3.1 Sometimes crack is caused by the impact load due to suction nozzle in pick and place operation. In pick and place operation, if the low dead point is too low, excessive stress is applied to component. This may cause cracks in the ceramic capacitor, therefore it is required to move low dead point of a suction nozzle to the higher level to minimize the board warp age and stress on the components. Nozzle pressure is typically adjusted to 1N to 3N (static load) during the pick and place operation.



3.2 Amount of Adhesive



Example: 0805 & 1206

а	a 0.2mm min.	
b	70 ~ 100 μm	
С	Do not touch the solder land	

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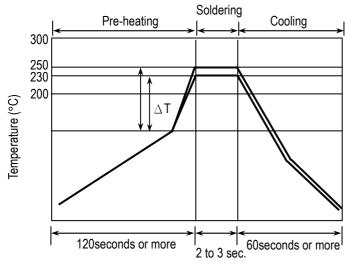


4. Soldering

4.1. Wave Soldering

Most of components are wave soldered with solder at 230 to $250\,^{\circ}$ C. Adequate care must be taken to prevent the potential of thermal cracks on the ceramic capacitors. Refer to the soldering methods below for optimum soldering benefits.

Recommend flow soldering temperature Profile



Soldering Method	Change in Temp.($^{\circ}$ C)
1206 and Under	$\Delta T \le 100 \sim 130 \text{ max}.$

To optimize the result of soldering, proper preheating is essential:

- 1) Preheat temperature is too low
 - a. Flux flows to easily
 - b. Possibility of thermal cracks
- 2) Preheat temperature is too high
 - a. Flux deteriorates even when oxide film is removed
 - b. Causes warping of circuit board
 - c. Loss of reliability in chip and other components

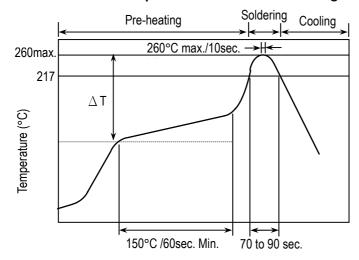
Cooling Condition:

Natural cooling using air is recommended. If the chips are dipped into a solvent for cleaning, the temperature difference (Δ T) between the solvent and the chips must be less than 100 °C.

4.2 Reflow Soldering

Preheat and gradual increase in temperature to the reflow temperature is recommended to decrease the potential of thermal crack on the components. The recommended heating rate depends on the size of component, however it should not exceed $3\,^{\circ}\text{C/Sec}$.

Recommend reflow profile for Lead-Free soldering temperature Profile (MIL-STD-202G #210F)



※ The cycles of soldering : Twice (max.)

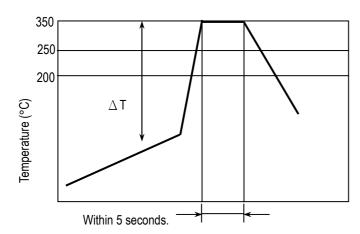
Soldering Method	Change in Temp.($^{\circ}$ C)
1206 and Under	∆T ≦ 190 °C
1210 and Over	∆T ≦ 130 °C

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4.3 Hand Soldering

Sudden temperature change in components, results in a temperature gradient recommended in the following table, and therefore may cause internal thermal cracks in the components. In general a hand soldering method is not recommended unless proper preheating and handling practices have been taken. Care must also be taken not to touch the ceramic body of the capacitor with the tip of solder Iron.



Soldering Method	Change in Temp.(°C)
1206 and Under	∆T ≦ 190 °C
1210 and Over	∆T ≦ 130 °C

How to Solder Repair by Solder Iron

1) Selection of the soldering iron tip

The required temperature of solder iron for any type of repair depends on the type of the tip, the substrate material, and the solder land size.

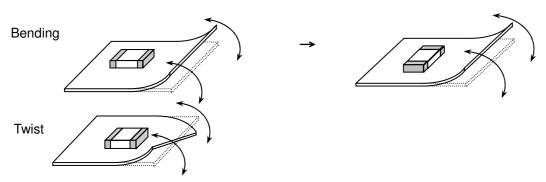
- 2) recommended solder iron condition
 - a.) Preheat the substrate to (60 ℃ to 120 ℃) on a hot plate. Note that due to the heat loss, the actual setting of the hot plate may have to be higher. (For example 100 ℃ to 150 ℃)
 - b.) Soldering iron power shall not exceed 30 W.
 - c.) Soldering iron tip diameter shall not exceed 3mm.
 - d.) Temperature of iron tip shall not exceed 350 ℃., and the process should be finished within 5 seconds. (refer to MIL-STD-202G)
 - f.) Do not touch the ceramic body with the tip of solder iron. Direct contact of the soldering iron tip to ceramic body may cause thermal cracks.
 - g.) After soldering operation, let the products cool down gradually in the room temperature.

5. Handling after chip mounted

5.1 Proper handling is recommended, since excessive bending and twist of the board, depends on the orientation of the chip on the board, may induce mechanical stress and cause internal crack in the capacitor.

Higher potential of crack

Lower potential of crack



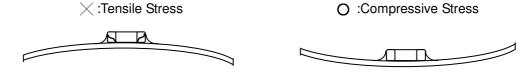
5.2 There is a potential of crack if board is warped due to excessive load by check pin



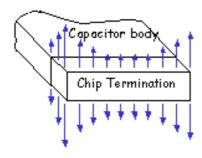
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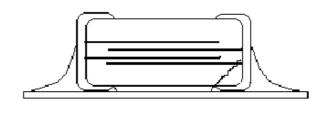


- 5.3 Mechanical stress due to warping and torsion.
 - (a) Crack occurrence ratio will be increased by manual separation.
 - (b) Crack occurrence ratio will be increased by tensile force, rather than compressive force.



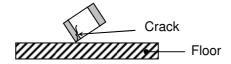
Capacitor Stress Analysis



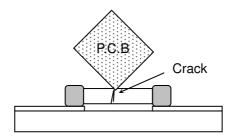


6. Handling of Loose Chip Capacitor

6.1 If dropped the chip capacitor may crack.



6.2 In piling and stacking of the P.C. boards after mounting for storage or handling, the corner of the P.C. board may hit the chip capacitor mounted on another board to cause crack.



7. Safekeeping condition and period

For safekeeping of the products, we recommend to keep the storage temperature between +5 to +40 °C and under humidity of 20 to 75% RH. The shelf life of capacitors is 6 months.

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